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Key indicators

Single-crystal X-ray study T = 180 KMean σ (S–P) = 0.007 Å R factor = 0.041 wR factor = 0.104 Data-to-parameter ratio = 16.6

For details of how these key indicators were automatically derived from the article, see http://journals.iucr.org/e.

$Cs_3Hf_2(P_2S_7)_2(PS_4)$

The first quaternary hafnium thiophosphate, tricaesium dihafnium pentaphosphorus octadecasulfide, $Cs_3Hf_2P_5S_{18}$ was synthesized by reacting HfS_2 with an *in situ* formed melt of Cs_2S_3 , P_2S_5 and S. The crystal structure is composed of a two-dimensional anionic $[Hf_2P_5S_{18}]^{3-}$ layer and intervening Cs^+ cations. Each of the two independent Hf^{4+} ions is surrounded by seven S atoms forming a distorted pentagonal bipyramid. The HfS_7 polyhedra are connected by an unusual edge- and corner-sharing arrangement of $[P_2S_7]$ groups and edge-sharing $[PS_4]$ tetrahedra into the final double-layered anion.

Comment

Until now, only a few quaternary alkali metal thiophosphates of group 4 metals have been structurally characterized (Cieren et al., 1994; Do et al., 1996; Derstroff et al., 2002). All quaternary compounds contain titanium as the transition metal. In our investigations of the A-M-P-S family (A = alkalimetal and M = group 4 metal), we prepared very recently the first quaternary zirconium thiophosphates, viz. A_3 Zr₂P₅S₁₈ (A = Rb, Cs) (Gutzmann et al., 2004), enhancing the range of structures of the A-M-P-S family. One interesting observation made in the past was that the ternary thiophosphates MP_2S_6 with M = Ti, Zr and Hf are not isostructural (Jandali *et* al., 1980; Simon et al., 1982, 1985; Lott et al., 1999). This observation was also made in the quaternary thiophosphates with the general formula $A_3M_2P_5S_{18}$, where the Ti compound is structurally quite different from the Zr compound. In our effort to investigate and determine the relationships between the cation size, the M:S ratio and the dimensionality of the structures in group 4 metal thiophosphates, we have obtained the new compound $Cs_3Hf_2P_5S_{18}$, which is isostructural with the Zr compound.

The crystal structure of $Cs_3Hf_2P_5S_{18}$ is built up of $[Hf_2P_5S_{18}]^{3-}$ layers extending in the (001) plane and charge-



Figure 1

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 $D_x = 3.152 \text{ Mg m}^{-3}$

Mo $K\alpha$ radiation Cell parameters from 8000

reflections

 $\begin{array}{l} \theta = 1.3 {-} 23.3^{\circ} \\ \mu = 11.51 \ \mathrm{mm}^{-1} \end{array}$

T = 180 (2) K

Plate, yellow

 $\begin{aligned} R_{\rm int} &= 0.041 \\ \theta_{\rm max} &= 23.1^\circ \end{aligned}$

 $h = -10 \rightarrow 10$

 $k = -10 \rightarrow 10$

 $l = -37 \rightarrow 37$

 $(\Delta/\sigma)_{\rm max} = 0.001$

 $\Delta \rho_{\rm max} = 1.82 \text{ e} \text{ Å}^2$

Friedel pairs

 $\Delta \rho_{\rm min} = -1.87 \text{ e } \text{\AA}^{-3}$

Extinction correction: SHELXL97

Flack parameter = 0.010 (13); 2064

Extinction coefficient: 0.00031 (3) Absolute structure: Flack (1983)

 $0.2 \times 0.2 \times 0.1 \text{ mm}$

4211 independent reflections

4119 reflections with $I > 2\sigma(I)$



Figure 2

Interconnection of the two distinct HfS_7 polyhedra *via* pentadentate $[P_2S_7]$ groups.

compensating Cs⁺ cations. The main feature of this structure type is the presence of HfS₇ polyhedra which are interconnected via pentadentate [P₂S₇] groups and tetradentate [PS₄] tetrahedra into a double-layered structure. Each of the two distinct Hf⁴⁺ ions is surrounded by seven S atoms forming a distorted pentagonal bipyramid. The mean Hf-S bond lengths of 2.617 (5) Å in the Hf1S₇ polyhedron and 2.621 (5) Å for Hf2S₇ are in good agreement with the sum of the ionic radii [1.84 Å for S^{2-} and 0.76 Å for $Hf^{4+}(CN7)$; Shannon, 1976]. The Hf1S₇ and Hf2S₇ polyhedra are linked via one $[P_2S_7]$ group that acts in an unusual pentadentate fashion. Each of the HfS₇ groups shares two common edges and one corner with two symmetry-related $[P_2S_7]$ units. Furthermore, the Hf1S₇ and Hf2S₇ polyhedra are interconnected via tetradentate [PS₄] tetrahedra into the final double-layered structure. The average P-S distances in the two unique pyrothiophosphate ligands and the $[PS_4]$ tetrahedra are 2.050, 2.052 and 2.038 Å. The longest P-S bonds in the $[P_2S_7]$ groups are observed for S atoms having bonds to two P atoms. The S-P-S angles in the thiophosphate ligands exhibit a significant distortion. The three crystallographically independent Cs⁺ cations are surrounded either by nine S atoms (average Cs1-S distance 3.739 Å and average Cs3-S distance 3.735 Å) or by ten S atoms (average Cs2–S distance 3.780 Å); these distances agree well with the sum of the ionic radii. The charge balance of the compound may be formulated as $[Cs^+]_3[Hf^{4+}]_2[PS_4^{3-}][P_2S_7^{4-}]_2$.

Experimental

The compound $Cs_3Hf_2P_5S_{18}$ was obtained by the reaction of Cs_2S_3 (0.3 mmol), HfS₂ (0.15 mmol), P_2S_5 (0.45 mmol) and S (1.5 mmol). Cs_2S_3 was prepared from stoichiometric amounts of Cs and S in liquid ammonia under an argon atmosphere. The starting materials were loaded into a quartz tube which was evacuated (10^{-3} mbar) and flame-sealed. The ampoule was heated to 873 K within 24 h. After 4 d, the sample was cooled down to 523 K at 2 K h⁻¹ and then to room temperature within 10 h. To remove unreacted $Cs_x P_y S_z$, the resultant melt was washed with dry *N*,*N*-dimethylformamide and diethyl ether. The product was dried in a vacuum and consisted of light-yellow plate-like crystals which are air- and moisture-sensitive.

Crystal data

 $\begin{array}{l} Cs_{3}Hf_{2}(P_{2}S_{7})_{2}(PS_{4})\\ M_{r} = 1487.64\\ Monoclinic, Cc\\ a = 9.3168 (4) Å\\ b = 9.8985 (6) Å\\ c = 34.0830 (17) Å\\ \beta = 94.236 (6)^{\circ}\\ V = 3134.6 (3) Å^{3}\\ Z = 4 \end{array}$

Data collection

Stoe IPDS diffractometer φ scans Absorption correction: numerical (*X-SHAPE* and *X-RED32*; Stoe & Cie, 1998) $T_{\min} = 0.120, T_{\max} = 0.312$ 9627 measured reflections

Refinement

Refinement on F^2 $R[F^2 > 2\sigma(F^2)] = 0.041$ $wR(F^2) = 0.104$ S = 1.154211 reflections 254 parameters $w = 1/[\sigma^2(F_o^2) + (0.0238P)^2 + 298.6042P]$ where $P = (F_o^2 + 2F_c^2)/3$

Table 1

Selected geometric parameters (Å, °).

Hf1-S7	2.554 (5)	P1-S4	2.172 (8)
$Hf1-S6^{i}$	2.586 (5)	P2-S7	2.023 (7)
Hf1-S9	2.604 (5)	P2-S5	2.039 (7)
Hf1-S8	2.615 (5)	P2-S6	2.046 (7)
Hf1-S3	2.618 (5)	P2-S4	2.115 (7)
Hf1-S2	2.632 (5)	P3-S9	2.017 (7)
Hf1-S5 ⁱ	2.713 (5)	P3-S10	2.037 (7)
Hf2-S14 ⁱⁱ	2.570 (5)	P3-S8	2.047 (7)
Hf2-S13	2.574 (5)	P3-S11	2.051 (7)
Hf2-S11	2.597 (5)	P4-S14	2.028 (8)
Hf2-S16 ⁱⁱ	2.611 (5)	P4-S12	2.031 (7)
$Hf2-S17^{ii}$	2.640 (5)	P4-S13	2.045 (7)
Hf2-S10	2.644 (5)	P4-S15	2.132 (7)
Hf2-S12	2.712 (5)	P5-S18	1.982 (8)
P1-S1	1.969 (8)	P5-S17	2.014 (8)
P1-S2	2.010 (7)	P5-S16	2.024 (7)
P1-S3	2.032 (8)	P5-S15	2.160 (8)
S1-P1-S2	119.8 (3)	S9-P3-S11	113.0 (3)
S1-P1-S3	116.4 (4)	S10-P3-S11	103.0 (3)
S2-P1-S3	101.9 (3)	S8-P3-S11	111.6 (3)
S1-P1-S4	103.4 (3)	S14-P4-S12	107.1 (3)
S2-P1-S4	105.1 (3)	S14-P4-S13	115.0 (3)
S3-P1-S4	109.6 (3)	S12-P4-S13	107.2 (3)
S7-P2-S5	105.7 (3)	S14-P4-S15	112.9 (3)
S7-P2-S6	115.8 (3)	S12-P4-S15	107.1 (3)
S5-P2-S6	108.2 (3)	S13-P4-S15	107.1 (3)
S7-P2-S4	113.3 (3)	S18-P5-S17	119.1 (3)
\$5-P2-S4	106.2 (3)	S18-P5-S16	115.1 (3)
S6-P2-S4	107.1 (3)	S17-P5-S16	101.8 (3)
S9-P3-S10	114.0 (3)	S18-P5-S15	103.6 (3)
S9-P3-S8	103.6 (3)	S17-P5-S15	106.6 (3)
S10-P3-S8	111.9 (3)	S16-P5-S15	110.4 (3)

Symmetry codes: (i) $x - \frac{1}{2}, \frac{1}{2} + y, z$; (ii) $x - \frac{1}{2}, y - \frac{1}{2}, z$.



Figure 3

Perspective view of the asymmetric unit of the title compound with the atomic labeling. Ellipsoids are drawn at the 50% probability level.

The absolute structure was determined and, according to the Flack x test, is in agreement with the selected setting. In addition, refinement of the inverse structure leads to significantly poorer reliability factors (R for all 4119 $F_o > 4\sigma(F_o) = 0.071$; wR for all reflections = 0.169).

Data collection: *IPDS Program Package* (Stoe & Cie, 1998); cell refinement: *IPDS Program Package*; data reduction: *IPDS Program Package*; program(s) used to solve structure: *SHELXS*97 (Sheldrick, 1997); program(s) used to refine structure: *SHELXL*97 (Sheldrick, 1997); molecular graphics: *DIAMOND* (Brandenburg, 1999); soft-

ware used to prepare material for publication: *CIFTAB* in *SHELXTL* (Bruker, 1998).

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